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<b>INFORMATION DISCLOSURE STATEMENT</b>	Case Name:	H.S. Fetterman 7-17
	Serial No.	
	Applicant:	H.S. Fetterman, et al.
	Filing Date:	
	Group:	

10/007904  
10/31/01

**U.S. PATENT DOCUMENTS**

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
EP	AA	4,918,377	Apr. 1990	Buehler et al.	324	691	12/5/88
EP	AB	4,319,396	Dec. 1979	Law et al.	29	571	12/28/79
EP	AC	Re. 32,625	Mar. 1988	Schwarz et al.	374	57	8/18/86
EP	AD	4,024,561	May 1977	Ghatalia	357	23	4/1/76
EP	AE	4,801,869	Jan. 1989	Sprogis	324	73	4/27/87
EP	AF	3,974,443	Aug. 1976	Thomas	324	64	1/2/75
EP	AG	5,268,329	Dec. 1993	Chittipeddi et al.	437	195	11/8/91
EP	AH	5,798,300	Aug. 1998	Chittipeddi et al.	438	627	5/15/97
EP	AI	5,972,179	Oct. 1999	Chittipeddi et al.	204	192.17	9/30/97
EP	AJ	5,244,839	Sep. 1993	Baker et al.	437	205	6/18/91
EP	AK	5,318,924	Jun. 1994	Lin et al.	437	192	1/22/93
EP	AL	5,300,307	Apr. 1994	Frerar et al.	427	96	9/14/92
EP	AM	5,264,377	Nov. 1993	Chesire et al.	437	8	4/3/92
EP	AN	5,049,811	Sep. 1991	Dreyer et al.	324	158	7/2/90
EP	AO	5,514,974	May 1996	Bouldin	324	763	10/12/94
	...						
	...						

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date	Country	Class	Subclass	Translation

**OTHER (including Author, Title, Date, Pertinent Pages, etc.)**

EP	AP	Technical Memorandum, "Acceleration of Stress-Migration Failure in Aluminum Interconnect," V. Ryan et al., AT&T Bell Laboratories, June 17, 1992.
EP	AQ	Journal of Electronic Materials, Vol. 24, No. 6, 1995, "Enhanced Stress-Migration Reliability for ULSI Interconnect: An Insight into the Perils of Screening Al Depositions Based on Grain Size," V. Ryan et al., pp. 969-974.
EP	AR	Circuits and Devices, "Stress-Voiding of Narrow Conductor Lines," F. G. Yost and F. E. Campbell, 1990 IEEE, pp. 40-44.

\*\*\*References listed beyond AZ would list as AA-1, AB-2, AC-3 thru AZ-26.

\*\*\*Note First Page ONLY Header/Footer. Subsequent pages must ONLY have page # layout as header

<b>EXAMINER</b> Evan Rert	<b>DATE CONSIDERED</b> 2/26/03
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\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609: Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant